

APPLICATION DATA SHEET

Electronic Version v14
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Title of Invention

METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN THE SEMICONDUCTOR INDUSTRY

Application Type: regular, utility
Attorney Docket Number: BUR920040086US1

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as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.

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